In the Abstract:

Please replace the Abstract with the following amended Abstract:

A method for performing a mask design layout resolution enhancement includes determining a level of correction for the design layout a mask design layout for a predetermined parametric yield with a minimum total correction cost. The <u>mask design</u> layout is corrected at the <u>a</u> determined level of correction based on a correction algorithm if the correction is required. In this manner, only those printed features on the <u>mask design</u> layout that are critical for obtaining the <u>a</u> desired performance yield are corrected, thereby reducing the total cost of correction of the <u>mask design</u> layout.